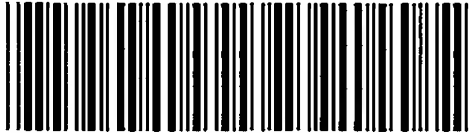


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
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	Examiner	Art Unit	
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73	592,865.8	7/22/2005	CHK
73	627	7/21/2005	CHK
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	DATE	EXMR
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